



N-Channel Enhancement-Mode Vertical DMOS Power FETs

Ordering Information

BV _{DSS} / BV _{DGS}	R _{DS(ON)} (max)	I _{D(ON)} (min)	Order Number / Package	
			DIE	WAFER
60V	0.3Ω	10A	VN2206ND	VN2206NW
100V	0.3Ω	10A	VN2210ND	VN2210NW

Features

- ☐ Freedom from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	±20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

*Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

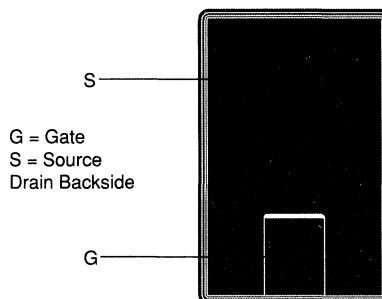
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and negative temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Specifications

- ☐ Die Size: 70 X 105 Mil
- ☐ Die Thickness: 11 ± 1.5 Mil
- ☐ Bonding Pad Size: Gate = 20 X 27 Mil
Source = 20 X 27 Mil
- ☐ Recommended Bonding Wire Size: 8 Mil
- ☐ Backside Metal: Au (CrAg optional)

Die Geometry



Thermal Characteristics (@ $\theta_{jc} = 1.25^\circ\text{C/W}$)

I_D (continuous)*	I_D (pulsed)*	I_{DR}	I_{DRM} *
8A	15A	8A	15A

* I_D (continuous) is limited by max rated T_J .

Electrical Characteristics (@ 25°C unless otherwise specified)

(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN2206	60		V	$V_{GS} = 0, I_D = 10\text{mA}$
		VN2210	100			
$V_{GS(th)}$	Gate Threshold Voltage	0.8		2.4	V	$V_{GS} = V_{DS}, I_D = 10\text{mA}$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature		-4.3	-5.5	mV/ $^\circ\text{C}$	$V_{GS} = V_{DS}, I_D = 10\text{mA}$
I_{GSS}	Gate Body Leakage		1	100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0$
I_{DSS}	Zero Gate Voltage Drain Current			50	μA	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
				10	mA	$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
$I_{D(ON)}$	ON-State Drain Current	3	5		A	$V_{GS} = 5\text{V}, V_{DS} = 25\text{V}$
		8				$V_{GS} = 10\text{V}, V_{DS} = 25\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		0.22	0.45	Ω	$V_{GS} = 5\text{V}, I_D = 1\text{A}$
			0.2	0.3		$V_{GS} = 10\text{V}, I_D = 4\text{A}$
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature		0.85	1.2	%/ $^\circ\text{C}$	$V_{GS} = 10\text{V}, I_D = 10\text{A}$
G_{FS}	Forward Transconductance	2.0	3.0		S	$V_{DS} = 25\text{V}, I_D = 2\text{A}$
C_{ISS}	Input Capacitance			500	pF	$V_{GS} = 0, V_{DS} = 25\text{V}$ $f = 1 \text{ MHz}$
C_{OSS}	Common Source Output Capacitance			300		
C_{RSS}	Reverse Transfer Capacitance			125		
$t_{d(ON)}$	Turn-ON Delay Time		8	15	ns	$V_{DD} = 25\text{V}$ $I_D = 5\text{A}$ $R_S = 50\Omega$
t_r	Rise Time		8	15		
$t_{d(OFF)}$	Turn-OFF Delay Time		70	90		
t_f	Fall Time		40	60		
V_{SD}	Diode Forward Voltage Drop		1.2	1.4	V	$V_{GS} = 0, I_{SD} = 4\text{A}$
t_{rr}	Reverse Recovery Time		500		ns	$V_{GS} = 0, I_{SD} = 1\text{A}$

Note 1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300 μs pulse, 2% duty cycle.)

Note 2: All A.C. parameters sample tested.

Switching Waveforms and Test Circuit

